Search Notes

370

Application/Control No.

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TOILLON ET AL.

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Examiner

Art Unit

Examiner

Rutkowski, Jeffrey

242 (physical layer and logical layer analysi concepts)s

2619

SEARCHED			
Class	Subclass	Date	Examiner
370	351, 389, 392, 401 (updated search)	08/22/2008	JMR

SEARCH NOTES		
Search Notes	Date	Examiner
searched EAST for logical and phyiscal layer analysis concepts	08/22/2008	JMR

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
370	242, 389, 401 (see attached notes)	08/2/20082	JMR	

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